

# **IGBT Die**

# PCFG50T65SQF

Using novel field stop IGBT technology, **onsemi**'s new series of field stop 4<sup>th</sup> generation IGBTs offer the optimum performance for solar inverter and UPS applications where low conduction and switching losses are essential.

#### **Features**

- Maximum Junction Temperature:  $T_I = 175^{\circ}C$
- Positive Temperature Co-efficient for Easy Parallel Operating
- High Current Capability
- Low Saturation Voltage:  $V_{CE(sat)} = 1.6 \text{ V (Typ.)}$  @  $I_C = 50 \text{ A}$
- High Input Impedance
- Fast Switching
- Tighten Parameter Distribution

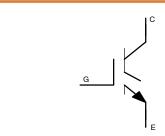
# **Typical Applications**

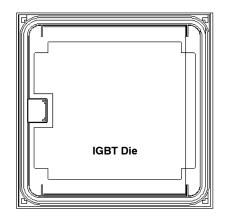
- Solar Inverters
- UPS Systems

#### **MECHANICAL DATA**

Parameter	Mils	μm		
Die Size	153.94 × 153.94	3910 x 3910		
Gate Pad Size	118.9 × 108.58	3020 x 2758		
Emitter Pad Size	14.05 × 17.68	357 x 449.2		
Die Thickness	2.48	63		
Scribe Width	80 μm			
Top Metal	5 μm AlSiCu			
Back Metal	1.05 μm Al/NiV/Ag			
Topside Passivation	Silicon Nitride			
Wafer Diameter	200 mm			
Max Possible Die Per Wafer	1743			
Recommended Storage Environment	In original container, in dry nitrogen, < 3 months at ambient temperature of 23°C			

# $V_{RCE}$ = 650 V $I_{C}$ = Limited by $T_{j(max)}$





**DIE Outline** 

#### **ORDERING INFORMATION**

Device	Inking?	Shipping Method		
PCFG50T65SQF	No	Sawn Wafer on Tape		

## **MAXIMUM RATINGS**

Parameter	Symbol	Value	Unit
Collector to Emitter Voltage, T <sub>J</sub> = 25°C	V <sub>CES</sub>	650	V
Gate to Emitter Voltage	$V_{GES}$	±20	V
Collector Current @T <sub>C</sub> = 25°C	I <sub>C</sub>	(Note 1)	Α
Pulsed Collector Current	I <sub>CM</sub>	200	А
Operating Junction Temperature	TJ	-40 to +175	°C
Storage Temperature Range	T <sub>STG</sub>	–17 to +25	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Depending on the thermal properties of assembly.
- 2. Not subject to production test verified by design/characterization.

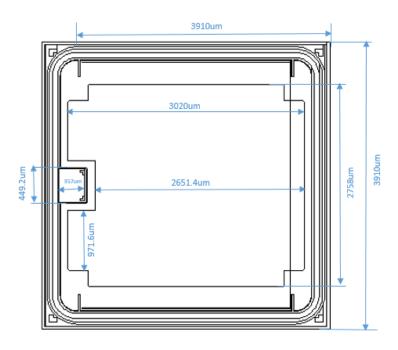
#### PCFG50T65SQF

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25$ °C unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Collector-Emitter Breakdown Voltage	V <sub>GE</sub> = 0 V, I <sub>C</sub> = 1 mA	BV <sub>CES</sub>	650			V
Temperature Coefficient of Breakdown Voltage	I <sub>C</sub> = 1 mA, reference to 25°C	$\Delta BV_{CES}/\Delta T_{J}$		0.6		V/°C
Collector-Emitter Cutoff Current	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = V <sub>CES</sub>	I <sub>DSS</sub>			250	μΑ
Gate Leakage Current	V <sub>CE</sub> = 0 V, V <sub>GE</sub> = V <sub>GES</sub>	I <sub>GSS</sub>			±400	nA
ON CHARACTERISTICS						
G-E Threshold Voltage	$V_{GE} = V_{CE}$ , $I_C = 50 \text{ mA}$	V <sub>GE(th)</sub>	2.6	4.5	6.4	V
Collector-Emitter Saturation Voltage	I <sub>C</sub> = 50 A, V <sub>GE</sub> = 15 V	V <sub>CE(sat)</sub>		1.6	2.1	V
	I <sub>C</sub> = 50 A, V <sub>GE</sub> = 15 V, T <sub>C</sub> = 175°C			1.92		V
DYNAMIC CHARACTERISTICS		-				
Input Capacitance	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 30 V, f = 1 MHz	C <sub>ies</sub>		3275		pF
Output Capacitance	1	Coes		84		
Reverse Transfer Capacitance	]	C <sub>res</sub>		12		
GATE CHARGE CHARACTERISTICS						
Total Gate Charge	V <sub>CE</sub> = 400 V, I <sub>C</sub> = 50 A, V <sub>GE</sub> = 15 V	$Q_g$		99		nC
Gate to Emitter Charge	1	Q <sub>ge</sub>		17		
Gate to Collector Charge	1	Q <sub>gc</sub>		23		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

<sup>3.</sup> For ordering, technique and other information on onsemi automotive bare die products, please contact automotivebaredie@onsemi.com.



(all dimensions in  $\mu$ m)

Figure 1. Die Layout

### **Further Electrical Characteristic**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

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